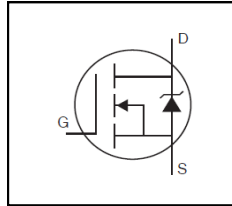


**Features**

- Advanced Process Technology
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Ease of Paralleling
- Simple Drive Requirements
- Lead-Free

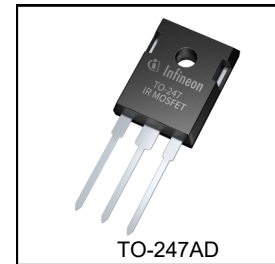


$V_{(BR)DSS}$	<b>200V</b>
$R_{DS(on)}$ max.	<b>0.075Ω</b>
$I_D$	<b>30A</b>

**Description**

IR MOSFET™ technology from Infineon utilizes advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and rugged device design that IR MOSFET™ devices are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-247 package is preferred for commercial-industrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because of its isolated mounting hole.



<b>G</b>	<b>D</b>	<b>S</b>
Gate	Drain	Source

Base part number	Package Type	Standard Pack		Orderable Part Number
		Form	Quantity	
IRFP250MPbF	TO-247AD	Tube	25	IRFP250MPbF

**Absolute Maximum Ratings**

Symbol	Parameter	Max.	Units
$I_D @ T_C = 25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$	30	A
$I_D @ T_C = 100^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$	21	
$I_{DM}$	Pulsed Drain Current ①⑤	120	
$P_D @ T_C = 25^\circ\text{C}$	Maximum Power Dissipation	214	W
	Linear Derating Factor	1.4	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 20	V
$E_{AS}$	Single Pulse Avalanche Energy ②⑤	315	mJ
$I_{AR}$	Avalanche Current ①⑤	30	A
$E_{AR}$	Repetitive Avalanche Energy ①	21	mJ
dv/dt	Peak Diode Recovery dv/dt③⑤	8.6	V/ns
$T_J$ $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to + 175	°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	
	Mounting torque, 6-32 or M3 screw	10 lbf·in (1.1N·m)	

**Thermal Resistance**

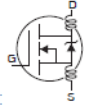
Symbol	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	—	0.7	°C/W
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.24	—	
$R_{\theta JA}$	Junction-to-Ambient	—	40	

**Electrical characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)**

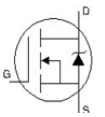
	Parameter	Min.	Typ.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	200	—	—	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA
ΔV <sub>(BR)DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temp. Coefficient	—	0.26	—	V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance	—	—	0.075	Ω	V <sub>GS</sub> = 10V, I <sub>D</sub> = 18A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0	—	4.0	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA
g <sub>fs</sub>	Forward Trans conductance	17	—	—	S	V <sub>DS</sub> = 50V, I <sub>D</sub> = 18A④
I <sub>DSS</sub>	Drain-to-Source Leakage Current	—	—	25	μA	V <sub>DS</sub> = 200V, V <sub>GS</sub> = 0V
		—	—	250		V <sub>DS</sub> = 160V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 150°C
I <sub>GSS</sub>	Gate-to-Source Forward Leakage	—	—	100	nA	V <sub>GS</sub> = 20V
	Gate-to-Source Reverse Leakage	—	—	-100		V <sub>GS</sub> = -20V

**Dynamic Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)**

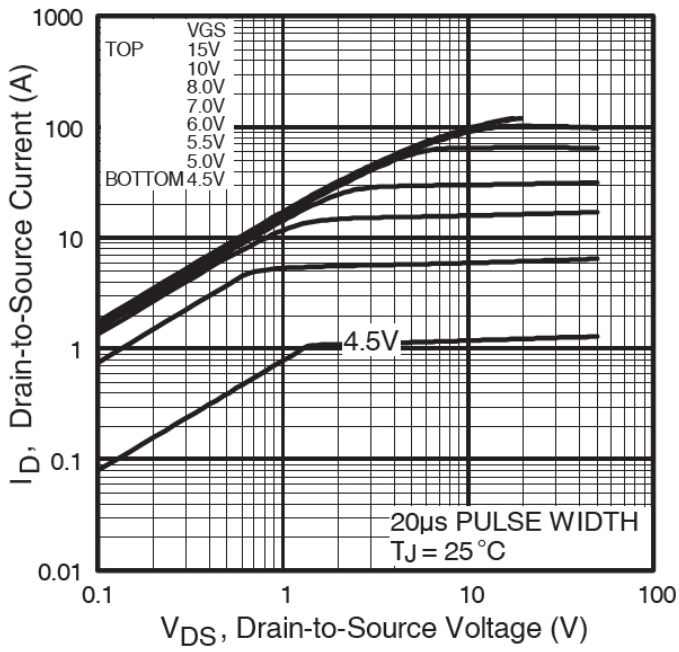
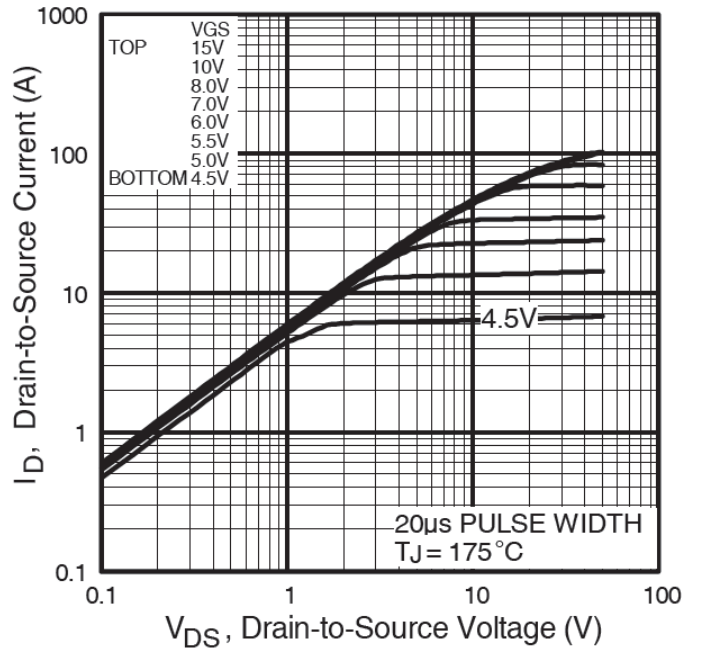
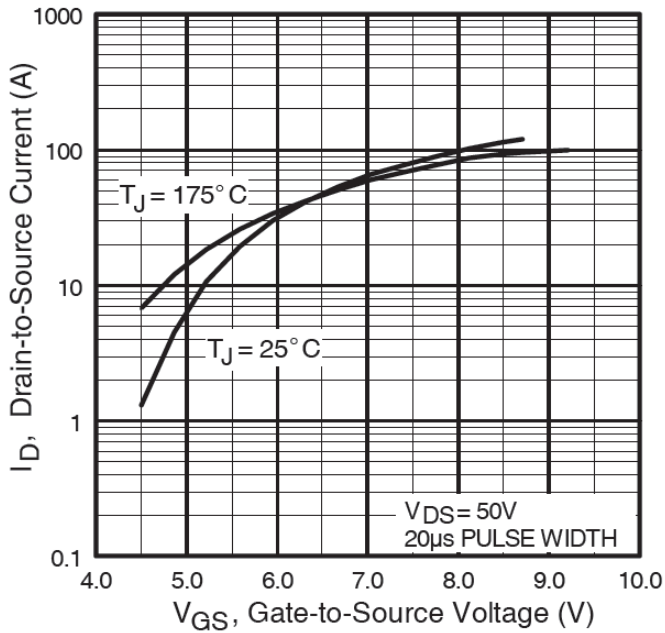
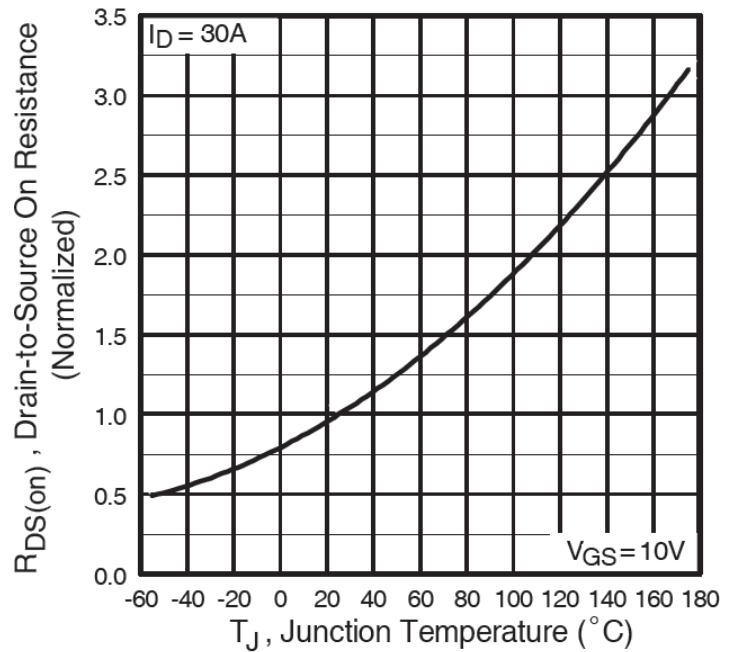
Q <sub>g</sub>	Total Gate Charge	—	—	123	nC	I <sub>D</sub> = 18A V <sub>DS</sub> = 160V V <sub>GS</sub> = 10V, See Fig.6 and 13 ④
Q <sub>gs</sub>	Gate-to-Source Charge	—	—	21		
Q <sub>gd</sub>	Gate-to-Drain Charge	—	—	57		
t <sub>d(on)</sub>	Turn-On Delay Time	—	14	—	ns	V <sub>DD</sub> = 100V I <sub>D</sub> = 18A R <sub>G</sub> = 3.9Ω R <sub>D</sub> = 5.5Ω, See Fig.10④
t <sub>r</sub>	Rise Time	—	43	—		
t <sub>d(off)</sub>	Turn-Off Delay Time	—	41	—		
t <sub>f</sub>	Fall Time	—	33	—		
L <sub>D</sub>	Internal Drain Inductance	—	5.0	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact
L <sub>S</sub>	Internal Source Inductance	—	13	—		
C <sub>iss</sub>	Input Capacitance	—	2159	—	pF	V <sub>GS</sub> = 0V V <sub>DS</sub> = 25V f = 1.0MHz, See Fig.5
C <sub>oss</sub>	Output Capacitance	—	315	—		
C <sub>rss</sub>	Reverse Transfer Capacitance	—	83	—		

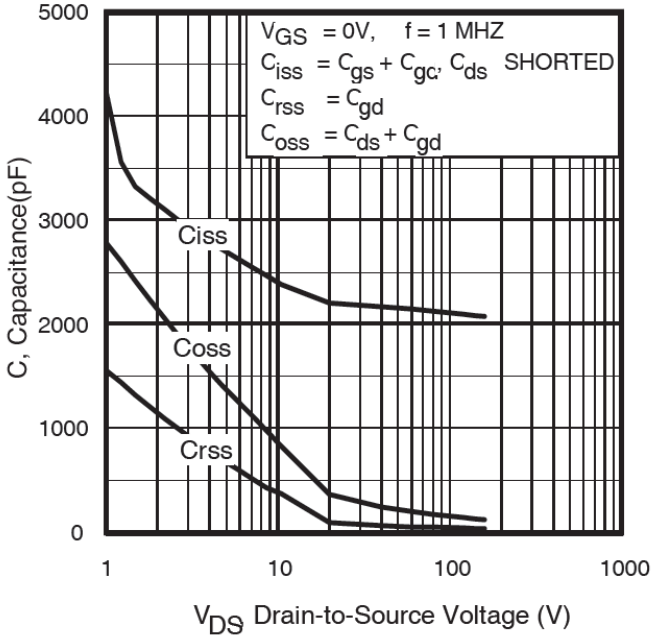

**Diode Characteristics**

	Parameter	Min.	Typ.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)	—	—	30	A	MOSFET symbol showing the integral reverse p-n junction diode.
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①	—	—	120		
V <sub>SD</sub>	Diode Forward Voltage	—	—	1.3	V	T <sub>J</sub> = 25°C, I <sub>S</sub> = 18A, V <sub>GS</sub> = 0V ④
t <sub>rr</sub>	Reverse Recovery Time	—	186	279	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> = 18A
Q <sub>rr</sub>	Reverse Recovery Charge	—	1.3	2.0	μC	di/dt = 100A/μs ④

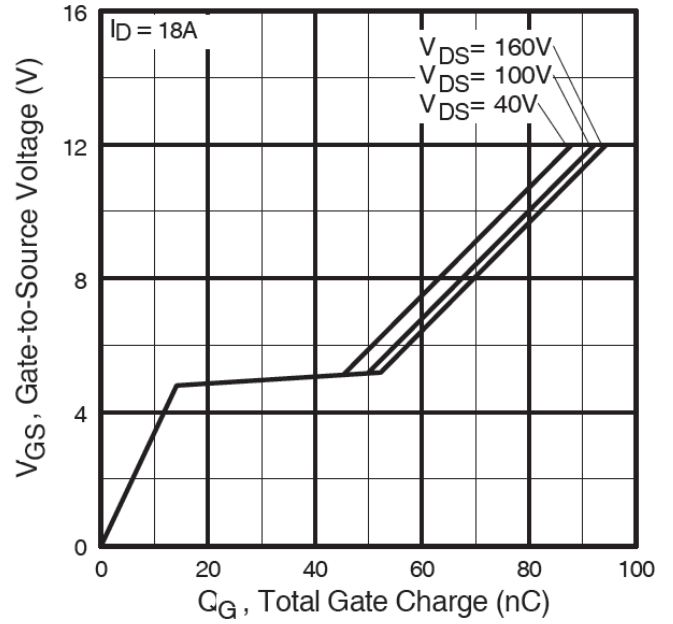

**Notes:**

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).
- ② Starting T<sub>J</sub> = 25°C, L = 1.9mH, R<sub>G</sub> = 25Ω, I<sub>AS</sub> = 18A. (See fig. 12).
- ③ I<sub>SD</sub> ≤ 18A, di/dt ≤ 374A/μs, V<sub>DD</sub> ≤ V<sub>(BR)DSS</sub>, T<sub>J</sub> ≤ 175°C.
- ④ Pulse width ≤ 300μs; duty cycle ≤ 2%.

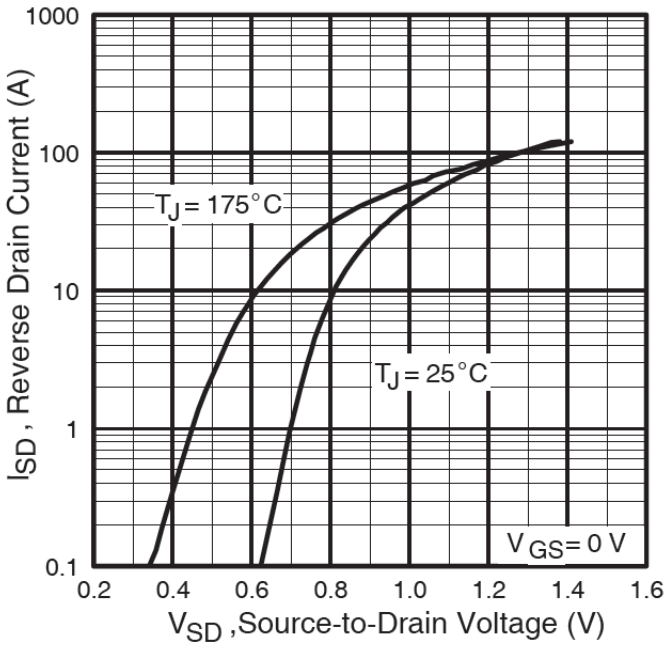

**Fig. 1** Typical Output Characteristics

**Fig. 2** Typical Output Characteristics

**Fig. 3** Typical Transfer Characteristics

**Fig. 4** Normalized On-Resistance vs. Temperature



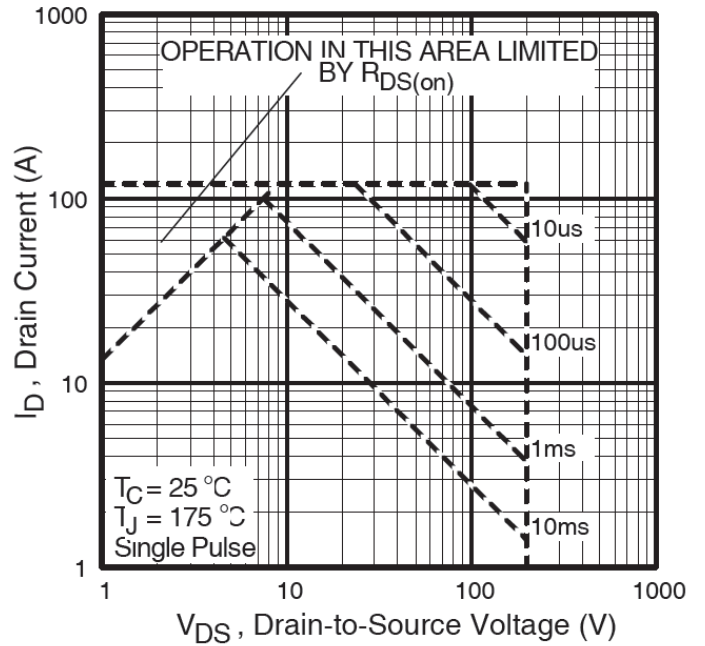
**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage



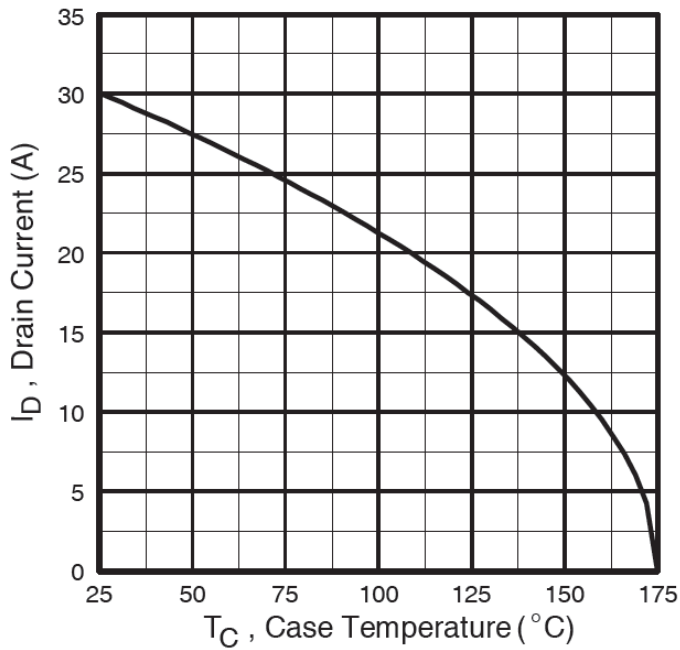
**Fig 6.** Typical Gate Charge vs. Gate-to-Source Voltage



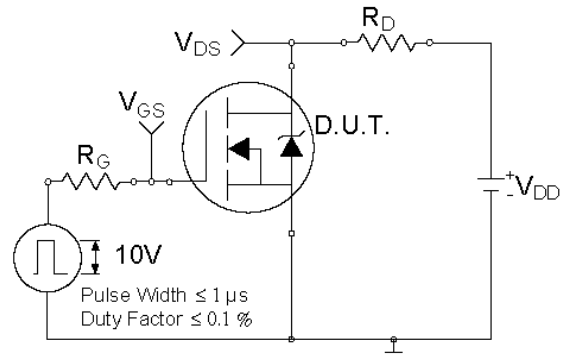
**Fig. 7** Typical Source-to-Drain Diode Forward Voltage



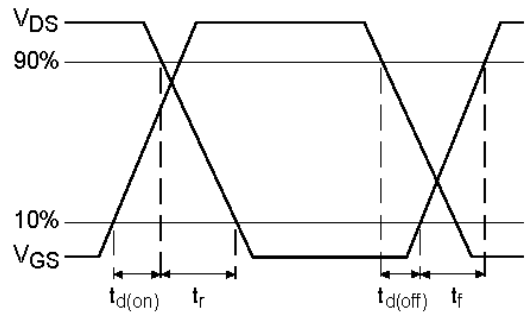
**Fig 8.** Maximum Safe Operating Area



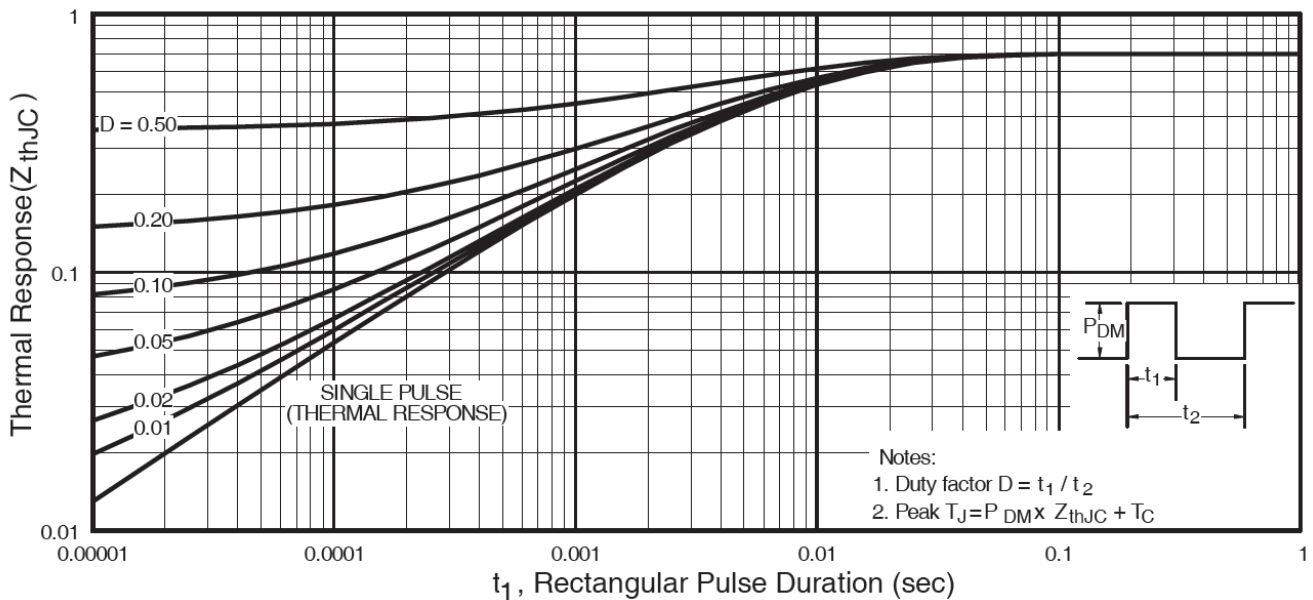
**Fig 9.** Maximum Drain Current vs. Case Temperature



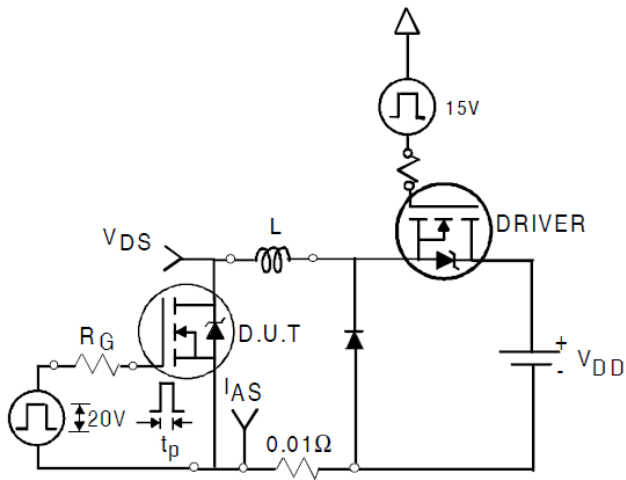
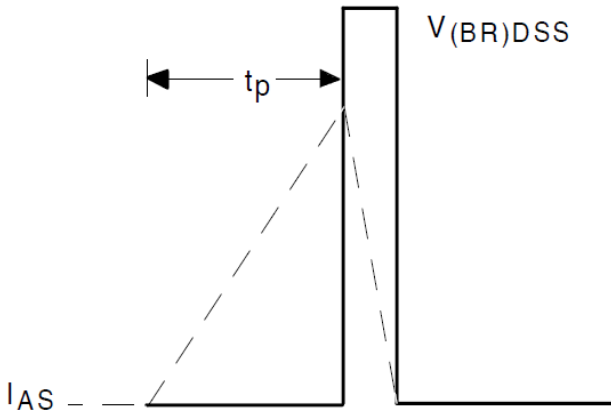
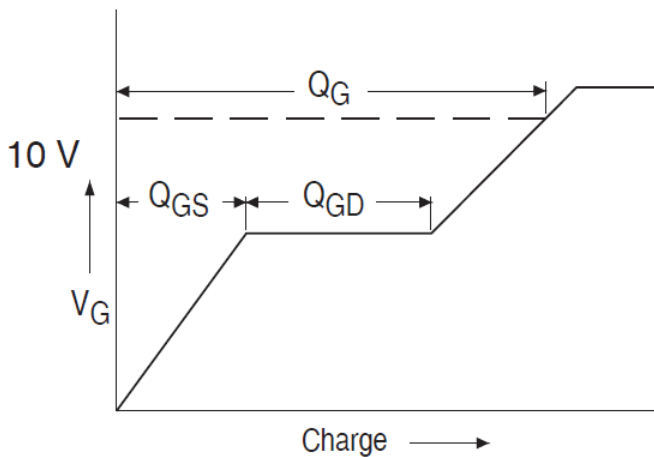
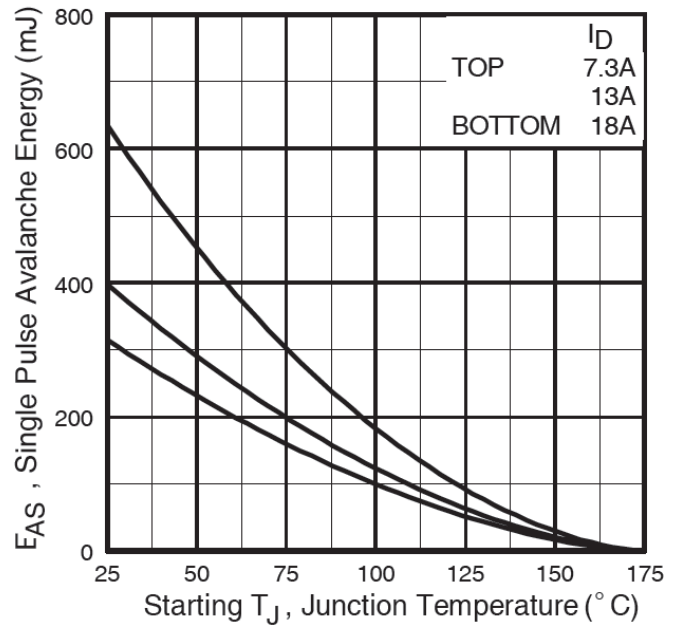
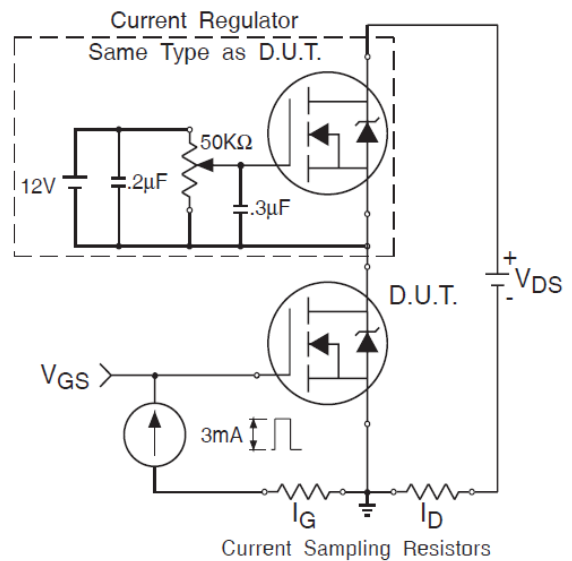
**Fig 10a.** Switching Time Test Circuit

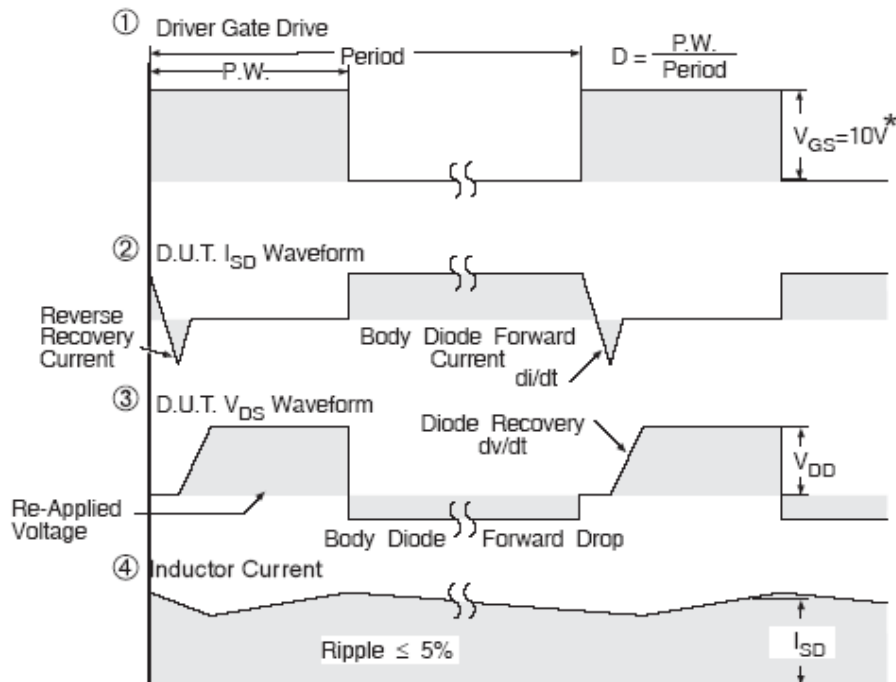
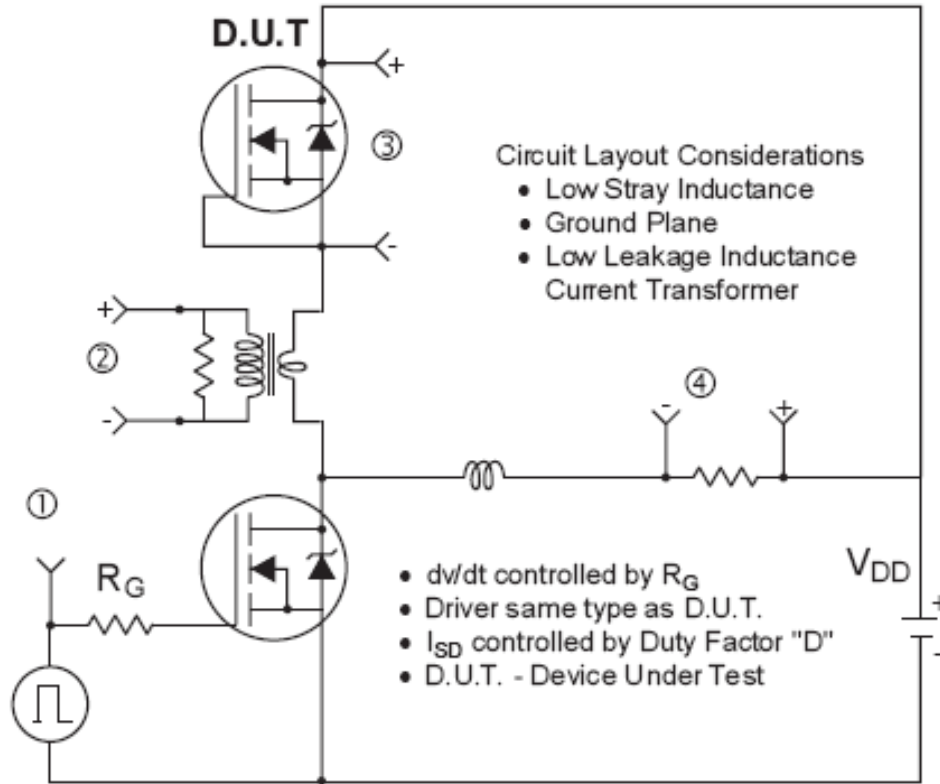


**Fig 10a.** Switching Time Waveforms



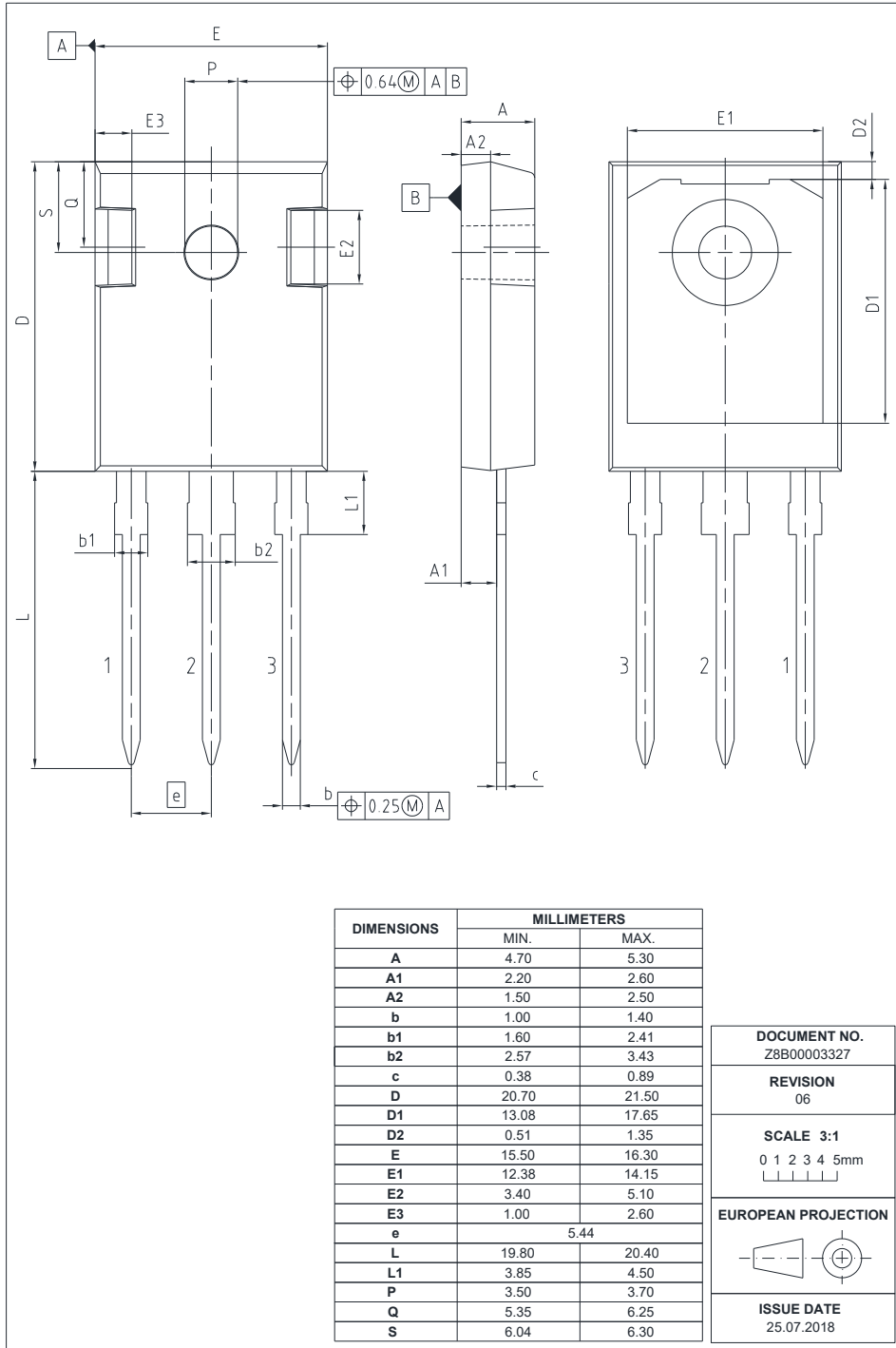
**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Case


**Fig. 12a.** Unclamped Inductive Test Circuit

**Fig. 12b.** Unclamped Inductive Waveforms

**Fig 13a.** Basic Gate Charge Waveform

**Fig 12c.** Maximum Avalanche Energy vs. Drain Current

**Fig 13b.** Gate Charge Test Circuit



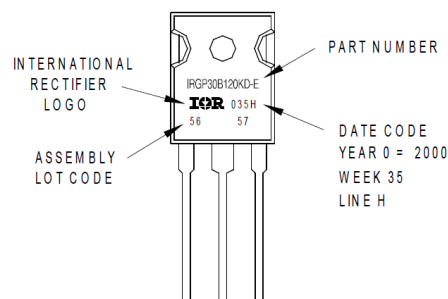
\*  $V_{GS} = 5V$  for Logic Level Devices

**Fig 14.** Peak Diode Recovery  $dv/dt$  Test Circuit for N-Channel IR MOSFET™

**TO-247AD Package Outline (Dimensions are shown in millimeters (inches))**

**TO-247AD Part Marking Information**

EXAMPLE: THIS IS AN IRGP30B120KD-E  
WITH ASSEMBLY  
LOT CODE 5657  
ASSEMBLED ON WW 35, 2000  
IN THE ASSEMBLY LINE "H"

Note: "P" in assembly line position  
indicates "Lead-Free"





**Revision History**

Date	Comments
05/28/2020	<ul style="list-style-type: none"> <li>• Updated datasheet with corporate template</li> <li>• Updated Package picture-page1</li> <li>• Corrected from “Hexfet power MOSFET” to “ IR MOSFET™” -page1 &amp;7</li> <li>• Corrected part marking from TO-247AC to TO-247AD on page 8.</li> </ul>

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